

Search Notes

Application/Control No.

10/713,627

Examiner

Duc M. Nguyen

Applicant(s)/Patent under
Reexamination

KARR ET AL.

Art Unit

2685

SEARCHED

Class	Subclass	Date	Examiner
455	550 552.1 553.1		
	556.1		
	557 41.1		
	41.2 41.3		
	515 102		
	108 110		
	115.1		
	115.3		
	161.1		
	161.3		
	226.2		
	205 208		
	334	2/28/2006	<i>✓</i>

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner